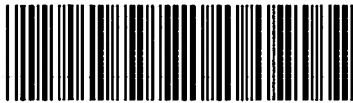


**Search Notes**

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Examiner

PAUL T. CHIN

Applicant(s)/Patent under  
Reexamination

HAN ET AL.

Art Unit

3652

**SEARCHED**

Class	Subclass	Date	Examiner
294	119.1	3/15/2006	PTC
	88	3/15/2006	PTC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR